Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/681,737	MIYA ET AL.	
Examiner	Art Unit	
Anh T. Mai	2832	

	SEAR	CHED	
Class	Subclass	Date	Examiner
336	115,117 118,130 131-132	5/27/2005	АМ
324	207.11	5/27/2005	AM

INT	ERFERENC	CE SEARCH	ED
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Same As above		5/27/2005	АМ

SEARCH NOT (INCLUDING SEARCH	TES STRATEGY))
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